

## 500V N-Channel Enhancement Mode MOSFET

### Description

The AP9N50D is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

### General Features

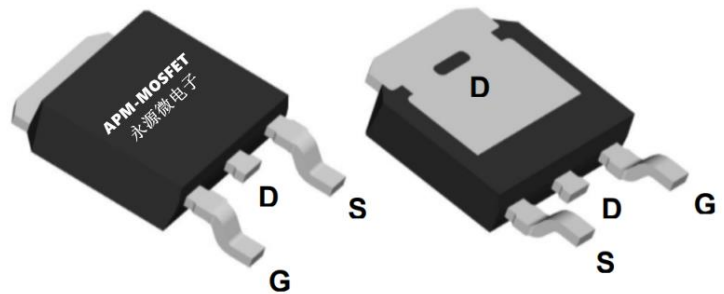
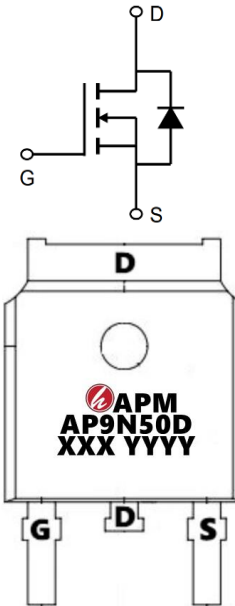
$V_{DS} = 500V$   $I_D = 9A$

$R_{DS(ON)} < 720m\Omega$  @  $V_{GS}=10V$  (Type: 630m $\Omega$ )

### Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP9N50D	TO-252-3L	AP9N50D XXX YYYY	2500

### Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-Source Voltage ( $V_{GS} = 0V$ )	500	V
$I_D$	Continuous Drain Current	9	A
$I_{DM}$	Pulsed Drain Current (note1)	36	A
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy (note2)	347	mJ
$I_{AR}$	Avalanche Current (note1)	9	A
$E_{AR}$	Repetitive Avalanche Energy (note1)	22	mJ
$P_D$	Power Dissipation ( $T_c = 25^\circ C$ )	178	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^\circ C$
$R_{thJC}$	Thermal Resistance, Junction-to-Case	0.7	$^\circ C/W$
$R_{thJA}$	Thermal Resistance, Junction-to-Ambient	62.5	$^\circ C/W$

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### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

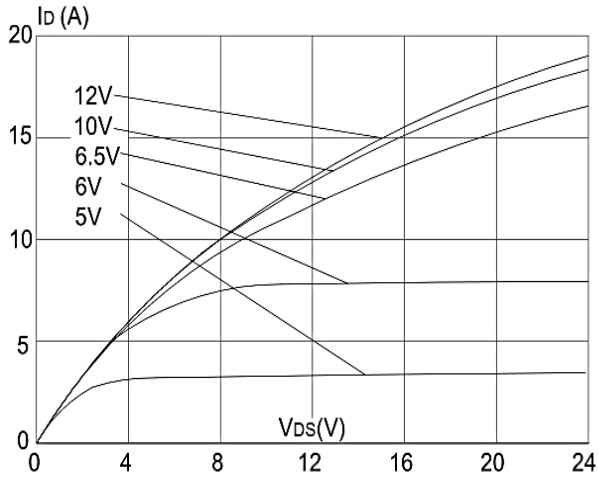
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	500	535	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> =500V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	-	-	1	μA
IGSS	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±30V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA	2	3	4	V
RDS(on)	Static Drain-Source on-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =4.5A	-	630	720	mΩ
Ciss	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1.0MHz	-	1100	-	pF
Coss	Output Capacitance		-	106	-	pF
Crss	Reverse Transfer Capacitance		-	32	-	pF
Qg	Total Gate Charge	V <sub>DD</sub> =400V, I <sub>D</sub> =9A, V <sub>GS</sub> =10V	-	19.5	-	nC
Qgs	Gate-Source Charge		-	4.6	-	nC
Qgd	Gate-Drain(“Miller”) Charge		-	7.1	-	nC
td(on)	Turn-on Delay Time	V <sub>DD</sub> =250V, I <sub>D</sub> =9A, R <sub>G</sub> =25Ω	-	24	-	ns
tr	Turn-on Rise Time		-	44	-	ns
td(off)	Turn-off Delay Time		-	55	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	35	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	9	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	36	A
VSD	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>SD</sub> =9A	-	-	1.4	V
trr	Reverse Recovery Time	V <sub>GS</sub> =0V, I <sub>S</sub> =9A, di/dt=100A/μs	-	332	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	3.5	-	μC

#### Note :

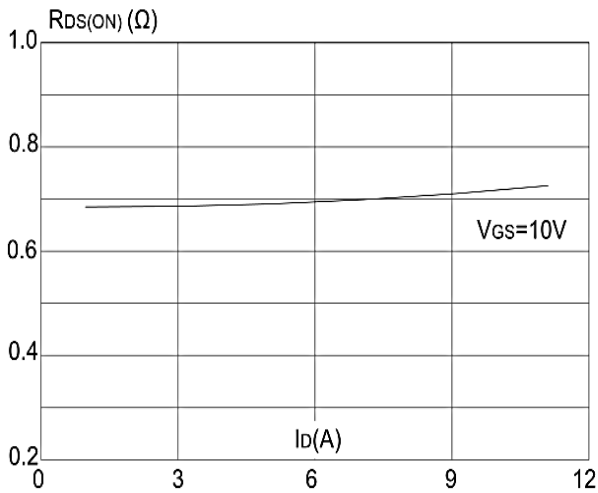
- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、The EAS data shows Max. rating . IAS=6A, VDD = 50V, RG = 25 Ω, Starting T<sub>J</sub> = 25 °C
- 3、The test condition is Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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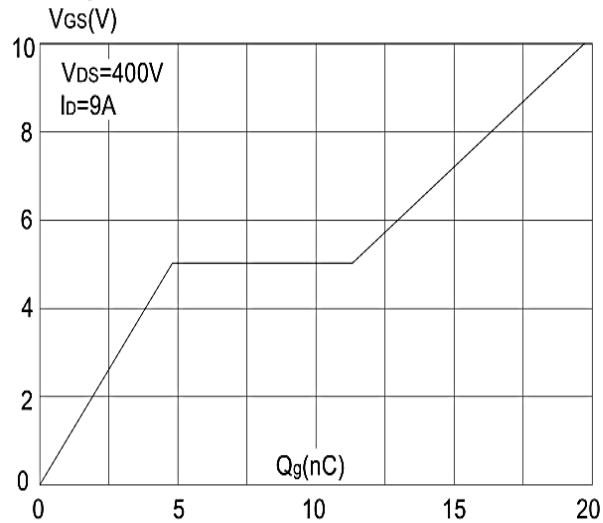
### Typical Characteristics



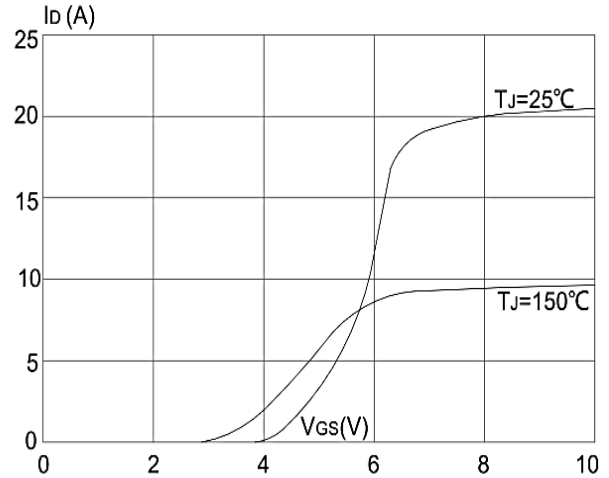
**Figure1: Output Characteristics**



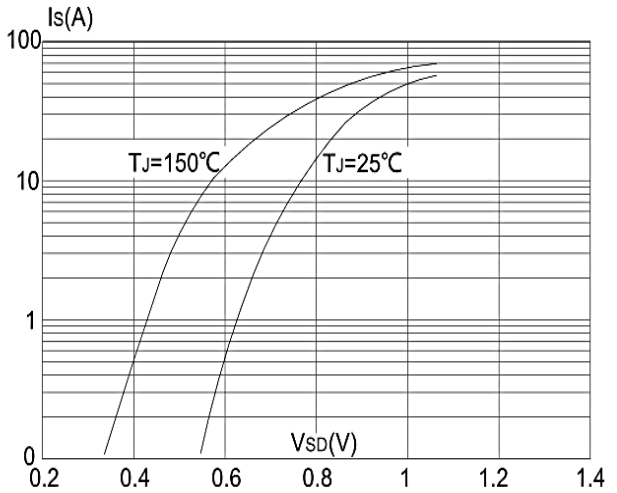
**Figure 3: On-resistance vs. Drain Current**



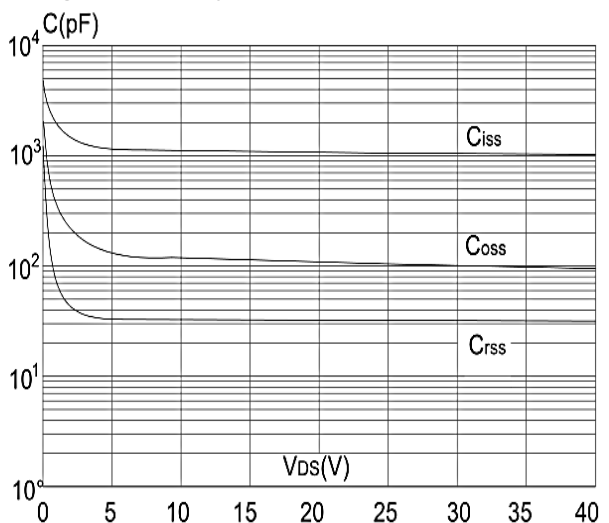
**Figure 5: Gate Charge Characteristics**



**Figure 2: Typical Transfer Characteristics**

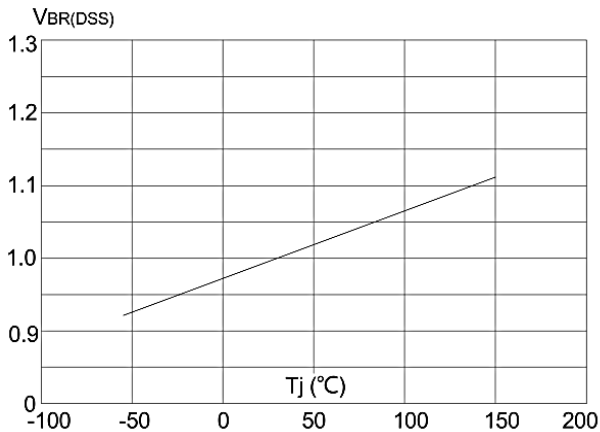


**Figure 4: Body Diode Characteristics**

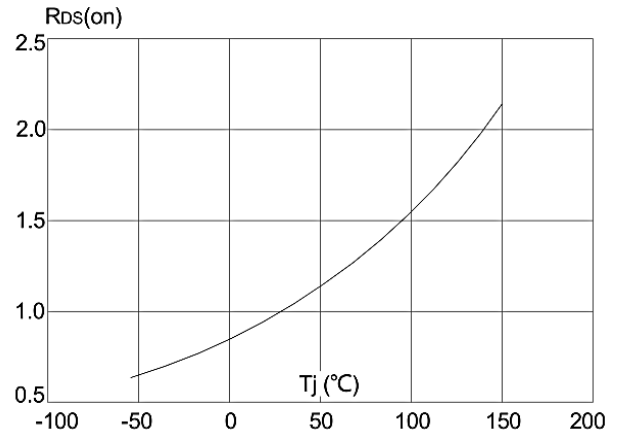


**Figure 6: Capacitance Characteristics**

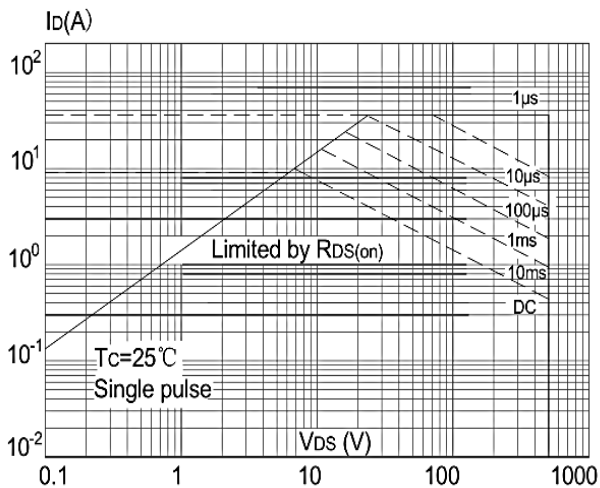
## 500V N-Channel Enhancement Mode MOSFET



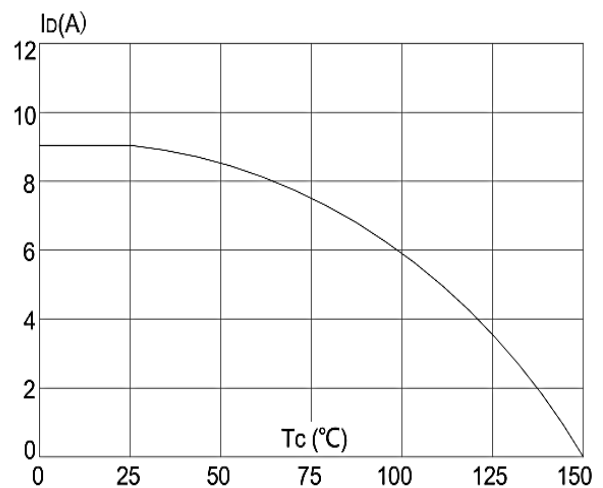
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**



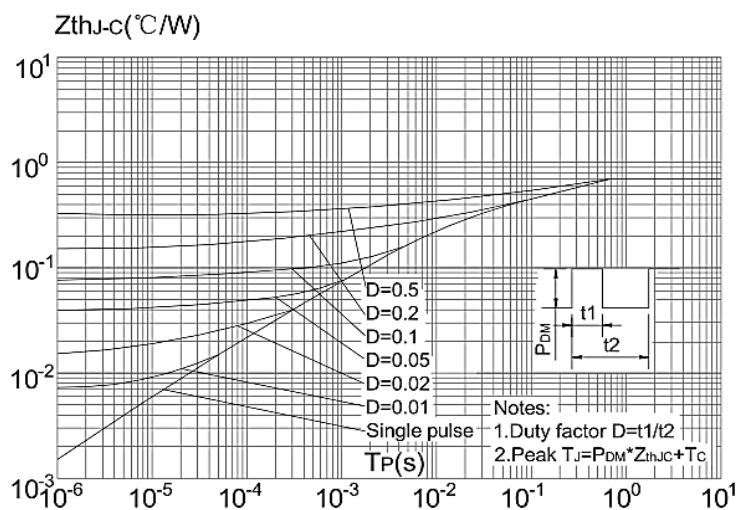
**Figure 8: Normalized on Resistance vs. Junction Temperature**



**Figure 9: Maximum Safe Operating Area vs. Case Temperature**



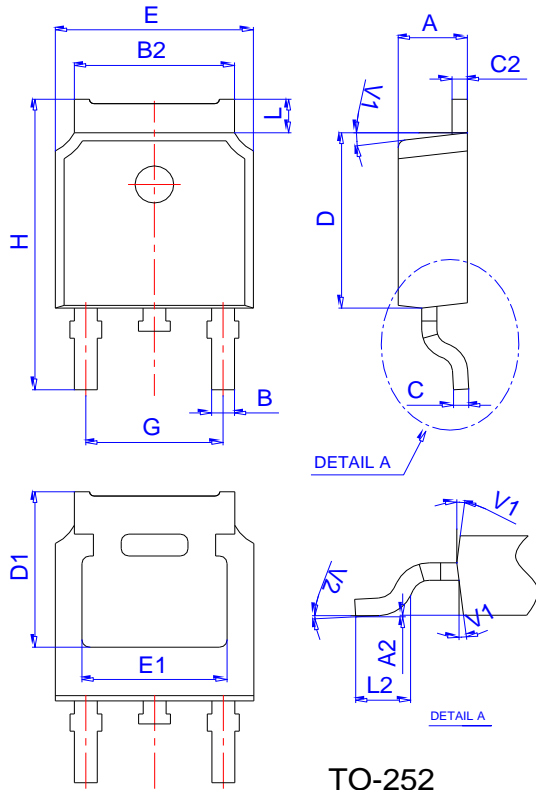
**Figure 10: Maximum Continuous Drain Current**



**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case**

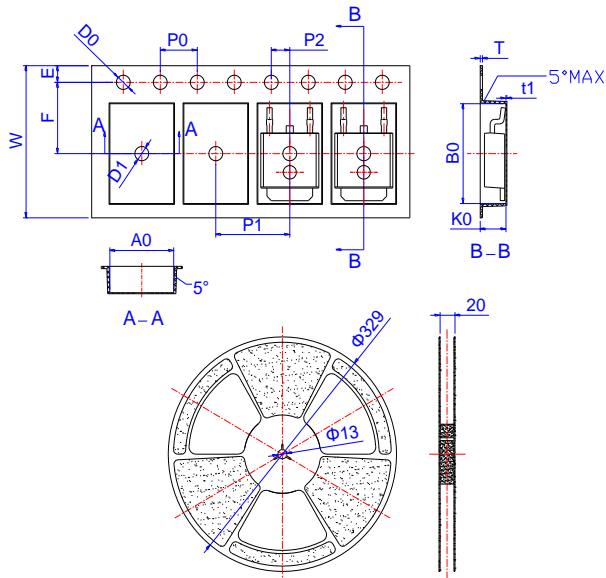
## 500V N-Channel Enhancement Mode MOSFET

### Package Mechanical Data:TO-252-3L



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

### Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

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Edition	Date	Change
Rve1.0	2021/1/31	Initial release

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